

**Search Notes**

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Examiner

Hai C. Pham

Applicant(s)/Patent under  
Reexamination

KOMIYA ET AL.

Art Unit

2861

**SEARCHED**

Class	Subclass	Date	Examiner
347	240, 251- 252, 144	6/16/2005	HP

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	6/16/2005	HP